

IN THE SPECIFICATION

Please amend the indicated paragraph as follows:

[0043] In one aspect, during substrate inspection the substrate surface is imaged, i.e., sampled, during the movement of the substrate 28 by the imaging system 150. For example, FIG. 7 illustrates the substrate 28 in position for the imaging system 150 to capture the image 32A at image position A. FIG. 8 illustrates ~~FIG. 9 illustrates~~ the substrate 28 in position for the imaging system 150 to capture an image 32G at image position G. ~~FIG. 9 illustrates~~ the substrate 28 in position for the imaging system 150 to capture the image 32I at image position I.